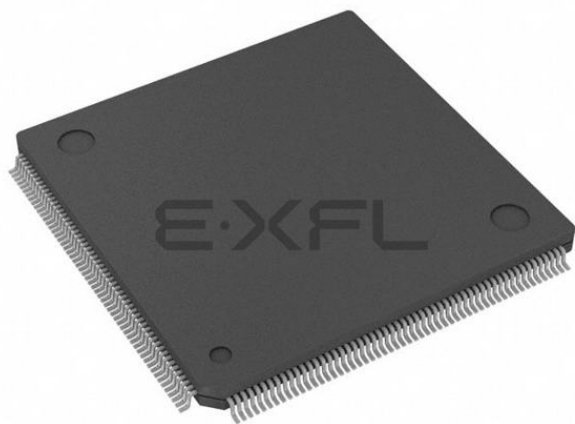




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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4F
Core Size	32-Bit Single-Core
Speed	200MHz
Connectivity	CANbus, CSIO, EBI/EMI, I ² C, LINbus, SD, SPI, UART/USART, USB
Peripherals	DMA, I ² S, LVD, POR, PWM, WDT
Number of I/O	190
Program Memory Size	2MB (2M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	256K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 32x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	216-LQFP
Supplier Device Package	216-LQFP (24x24)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/s6e2c5al0agl2000a

Low-power Consumption Mode

Six low power consumption modes are supported.

- Sleep
- Timer
- RTC
- Stop
- Deep standby RTC (selectable from with/without RAM retention)
- Deep standby stop (selectable from with/without RAM retention)

Peripheral Clock Gating

The system can reduce the current consumption of the total system with gating the operation clocks of peripheral functions not used.

VBAT

The consumption power during the RTC operation can be reduced by supplying the power supply independent from the RTC (calendar circuit)/32 kHz oscillation circuit. The following circuits can also be used.

- RTC
- 32-kHz oscillation circuit
- Power-on circuit
- Back up register: 32 bytes
- Port circuit

Debug

- Serial wire JTAG debug port (SWJ-DP)
- Embedded trace macrocells (ETM) provide comprehensive debug and trace facilities.
- AHB trace macrocells (HTM)

Unique ID

Unique value of the device (41-bit) is set.

Power Supply

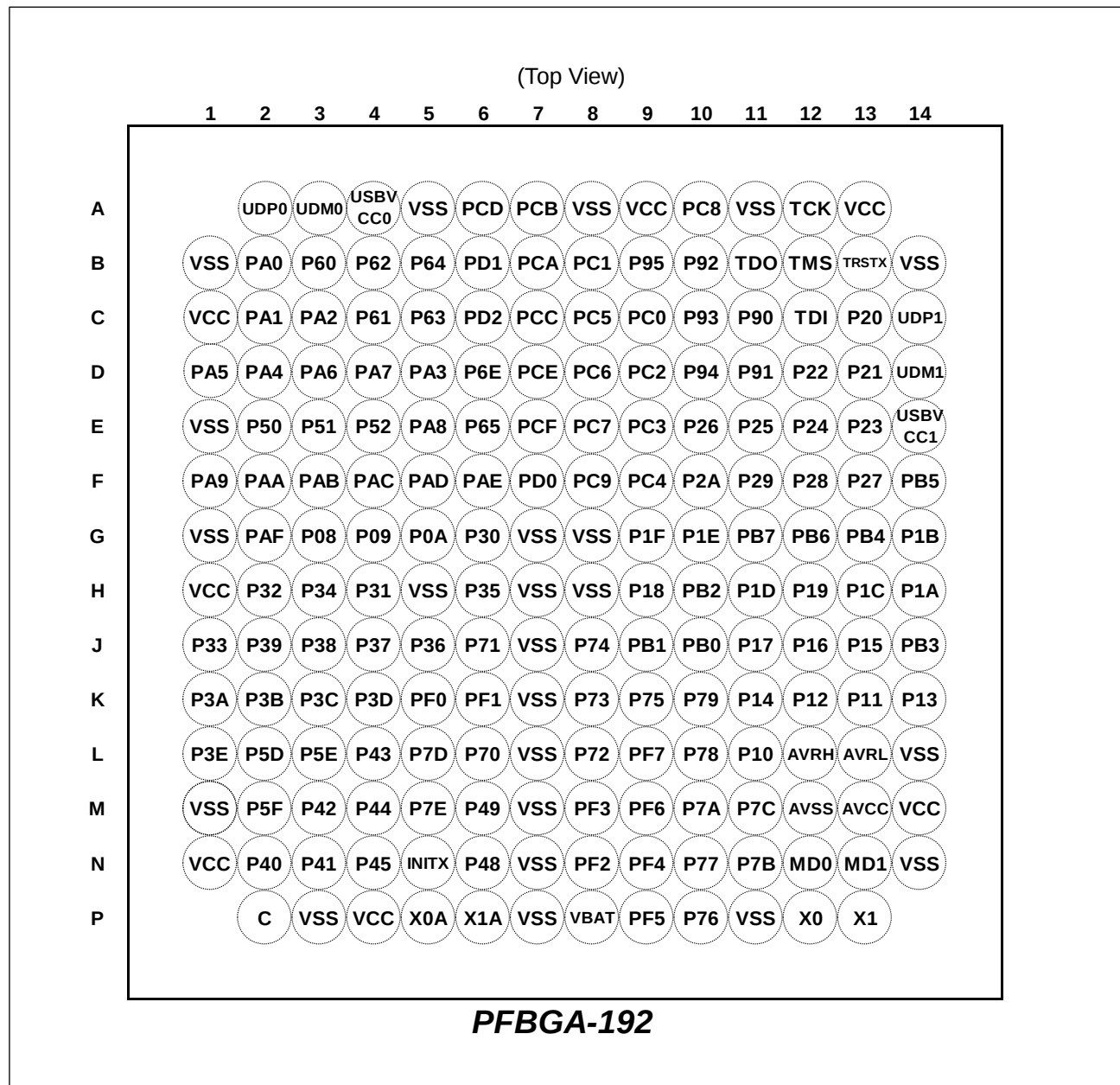
- Four power supplies
 - Wide range voltage:
VCC = 2.7 V to 5.5 V
 - Power supply for USB ch 0 I/O:
USBVCC0 = 3.0 V to 3.6 V (when USB is used)
= 2.7 V to 5.5 V (when GPIO is used)
 - Power supply for USB ch 1 I/O:
USBVCC1 = 3.0 V to 3.6 V (when USB is used)
= 2.7 V to 5.5 V (when GPIO is used)
 - Power supply for VBAT:
VBAT = 1.65 V to 5.5 V

Product Name		S6E2C58H0A S6E2C59H0A S6E2C5AH0A	S6E2C58J0A S6E2C59J0A S6E2C5AJ0A	S6E2C58L0A S6E2C59L0A S6E2C5AL0A
Built-in CR	High-speed	4 MHz		
	Low-speed	100 kHz		
Debug function		SWJ-DP/ETM/HTM		
Unique ID		Yes		

Notes:

- All signals of the peripheral function in each product cannot be allocated by limiting the pins of package. It is necessary to use the port relocate function of the I/O port according to your function use.
- See 12.4.3 Built-In CR Oscillation Characteristics for the accuracy of the built-in CR.

LBE192



Note:

- The number after the underscore ("_") in pin names such as XXX_1 and XXX_2 indicates the relocated port number. For these pins, there are multiple pins that provide the same function for the same channel. Use the extended port function register (EPFR) to select the pin.

Pin No				Pin Name	I/O circuit type	Pin state type
LQQ216	LQP176	LQS144	LBE192			
48	38	33	K3	P3C	G	K
				SIN13_0		
				RTO03_0 (PPG02_0)		
				TIOA3_1		
				INT19_1		
				MAD21_0		
				MNCLE_0		
49	39	34	K4	P3D	G	I
				SOT13_0 (SDA13_0)		
				RTO04_0 (PPG04_0)		
				TIOA4_1		
				MAD20_0		
				MNWEX_0		
50	40	35	L1	P3E	G	I
				SCK13_0 (SCL13_0)		
				RTO05_0 (PPG04_0)		
				TIOA5_1		
				MAD19_0		
				MNREX_0		
51	41	-	L2	P5D	E	K
				SIN10_1		
				TIOB11_2		
				INT01_2		
				MADATA29_0		
				I2SMCLK0_0		
52	42	-	L3	P5E	E	I
				SOT10_1 (SDA10_1)		
				TIOA12_2		
				MADATA30_0		
				I2SDO0_0		
53	43	-	M2	P5F	E	I
				SCK10_1 (SCL10_1)		
				TIOB12_2		
				MADATA31_0		
				I2SWS0_0		
54	44	36	M1	VSS	-	-
55	45	37	N1	VCC	-	-
56	46	38	N2	P40	G	K
				SIN3_1		
				RTO10_0 (PPG10_0)		
				TIOA0_0		
				AIN0_0		
				INT23_0		
				MCSX7_0		

Pin No				Pin Name	I/O circuit type	Pin state type
LQQ216	LQP176	LQS144	LBE192			
84	69	59	J8	P74	E	I
				SCK9_0 (SCL9_0)		
				TIOB2_0		
				MAD03_0		
85	70	-	N8	PF2	L	I
				RTO10_1 (PPG10_1)		
				TIOA6_1		
				MRASX_0		
86	71	-	M8	PF3	L	K
				RTO11_1 (PPG10_1)		
				TIOB6_1		
				INT05_1 MCASX_0		
87	72	-	N9	PF4	L	K
				RTO12_1 (PPG12_1)		
				TIOA7_1		
				INT06_1 MSDWEX_0		
88	73	-	P9	PF5	L	K
				RTO13_1 (PPG12_1)		
				TIOB7_1		
				INT07_1 MCSX8_0		
89	74	-	M9	PF6	L	K
				RTO14_1 (PPG14_1)		
				TIOA14_1		
				INT20_1 MSDCKE_0		
90	75	-	L9	PF7	L	K
				RTO15_1 (PPG14_1)		
				TIOB14_1		
				INT21_1 MSDCLK_0		
91	76	60	K9	P75	E	K
				SIN8_0		
				TIOB3_0		
				AIN1_0 INT20_0 MAD04_0		
92	77	61	P10	P76	E	I
				SOT8_0 (SDA8_0)		
				TIOB4_0		
				BIN1_0 MAD05_0		

Module	Pin name	Function	Pin No			
			LQQ 216	LQP 176	LQS 144	LBE 192
External Bus	MNALE_0	External bus interface ALE signal to control NAND Flash output pin	47	37	32	K2
	MNCLE_0	External bus interface CLE signal to control NAND Flash output pin	48	38	33	K3
	MNREX_0	External bus interface read enable signal to control NAND Flash	50	40	35	L1
	MNWEX_0	External bus interface write enable signal to control NAND Flash	49	39	34	K4
	MOEX_0	External bus interface read enable signal for SRAM	209	169	137	C5
	MWEX_0	External bus interface write enable signal for SRAM	210	170	138	B4
	MSDCLK_0	SDRAM interface SDRAM clock output pin	90	75	-	L9
	MSDCKE_0	SDRAM interface SDRAM clock enable output pin	89	74	-	M9
	MRASX_0	SDRAM interface SDRAM row active output pin	85	70	-	N8
	MCASX_0	SDRAM interface SDRAM column active output pin	86	71	-	M8
	MSDWEX_0	SDRAM interface SDRAM write enable output pin	87	72	-	N9
External Interrupt	INT00_0	External interrupt request 00 input pin	2	2	2	B2
	INT00_1		38	28	23	H3
	INT00_2		19	-	-	-
	INT01_0	External interrupt request 01 input pin	7	7	7	D1
	INT01_1		41	31	26	H6
	INT01_2		51	41	-	L2
	INT02_0	External interrupt request 02 input pin	14	13	10	E5
	INT02_1		42	32	27	J5
	INT02_2		26	-	-	-
	INT03_0	External interrupt request 03 input pin	17	16	13	F3
	INT03_1		43	33	28	J4
	INT03_2		34	24	-	G6
	INT04_0	External interrupt request 04 input pin	59	49	41	L4
	INT04_1		100	83	67	M11
	INT04_2		65	-	-	-
	INT05_0	External interrupt request 05 input pin	70	55	47	L5
	INT05_1		86	71	-	M8
	INT05_2		68	-	-	-

Module	Pin name	Function	Pin No			
			LQQ 216	LQP 176	LQS 144	LBE 192
GPIO	P50	General-purpose I/O port 5	10	10	-	E2
	P51		11	11	-	E3
	P52		12	12	-	E4
	P53		13	-	-	-
	P54		19	-	-	-
	P55		20	-	-	-
	P56		21	-	-	-
	P57		22	-	-	-
	P58		26	-	-	-
	P59		27	-	-	-
	P5A		28	-	-	-
	P5B		29	-	-	-
	P5C		33	-	-	-
	P5D		51	41	-	L2
	P5E		52	42	-	L3
	P5F		53	43	-	M2
	P60	General-purpose I/O port 6	212	172	140	B3
	P61		211	171	139	C4
	P62		210	170	138	B4
	P63		209	169	137	C5
	P64		208	168	-	B5
	P65		207	167	-	E6
	P66		206	-	-	-
	P67		205	-	-	-
	P68		204	-	-	-
	P69		203	-	-	-
	P6A		202	-	-	-
	P6B		201	-	-	-
	P6C		200	-	-	-
	P6D		199	-	-	-
	P6E		198	166	136	D6

Module	Pin name	Function	Pin No			
			LQQ 216	LQP 176	LQS 144	LBE 192
Multi-function serial 5	SIN5_0	Multi-function serial interface ch.5 input pin	147	121	97	F13
	SIN5_1		170	140	-	D11
	SOT5_0 (SDA5_0)	Multi-function serial interface ch.5 output pin.	146	120	96	F12
	SOT5_1 (SDA5_1)	This pin operates as SOT5 when it is used in a UART/CSIO/LIN (operation modes 0 to 3) and as SDA5 when it is used in an I ² C (operation mode 4).	171	141	-	B10
	SCK5_0 (SCL5_0)	Multi-function serial interface ch.5 clock I/O pin.	145	119	95	F11
	SCK5_1 (SCL5_1)	This pin operates as SCK5 when it is used in a CSIO (operation modes 2) and as SCL5 when it is used in an I ² C (operation mode 4).	172	142	-	C10
	CTS5_0	Multi-function serial interface ch.5 CTS input pin	144	118	94	F10
	CTS5_1		173	143	-	D10
	RTS5_0	Multi-function serial interface ch.5 RTS output pin	143	117	93	G9
	RTS5_1		174	144	-	B9
Multi-function serial 6	SIN6_0	Multi-function serial interface ch.6 input pin	96	79	63	L10
	SIN6_1		117	97	81	K14
	SOT6_0 (SDA6_0)	Multi-function serial interface ch.6 output pin.	97	80	64	K10
	SOT6_1 (SDA6_1)	This pin operates as SOT6 when it is used in a UART/CSIO/LIN (operation modes 0 to 3) and as SDA6 when it is used in an I ² C (operation mode 4).	118	98	82	K11
	SCK6_0 (SCL6_0)	Multi-function serial interface ch.6 clock I/O pin.	98	81	65	M10
	SCK6_1 (SCL6_1)	This pin operates as SCK6 when it is used in a CSIO (operation modes 2) and as SCL6 when it is used in an I ² C (operation mode 4).	126	102	-	J10
	SCS60_0	Multi-function serial interface ch.6 chip select 0 input/output pin	99	82	66	N11
	SCS60_1		127	103	-	J9
	SCS61_0	Multi-function serial interface ch.6 chip select1 input/output pin	100	83	67	M11
	SCS61_1		128	104	-	H10
	SCS62_0	Multi-function serial interface ch.6 chip select2 input/output pin	79	64	-	K6
	SCS62_1		129	105	-	J14
	SCS63_0	Multi-function serial interface ch.6 chip select3 input/output pin	78	63	-	K5
	SCS63_1		119	-	-	-

6. Handling Precautions

Every semiconductor device has a characteristic, inherent rate of failure. The possibility of failure is greatly affected by the conditions in which they are used (circuit conditions, environmental conditions, etc.). This page describes precautions that must be observed to minimize the chance of failure and to obtain higher reliability from your Cypress semiconductor devices.

6.1 Precautions for Product Design

This section describes precautions when designing electronic equipment using semiconductor devices.

Absolute Maximum Ratings

Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of certain established limits, called absolute maximum ratings. Do not exceed these ratings.

Recommended Operating Conditions

Recommended operating conditions are normal operating ranges for the semiconductor device. All the device's electrical characteristics are warranted when operated within these ranges.

Always use semiconductor devices within the recommended operating conditions. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their sales representative beforehand.

Processing and Protection of Pins

These precautions must be followed when handling the pins that connect semiconductor devices to power supply and I/O functions.

- 1. Preventing Over-Voltage and Over-Current Conditions**

Exposure to voltage or current levels in excess of maximum ratings at any pin is likely to cause deterioration within the device, and in extreme cases leads to permanent damage of the device. Try to prevent such overvoltage or over-current conditions at the design stage.

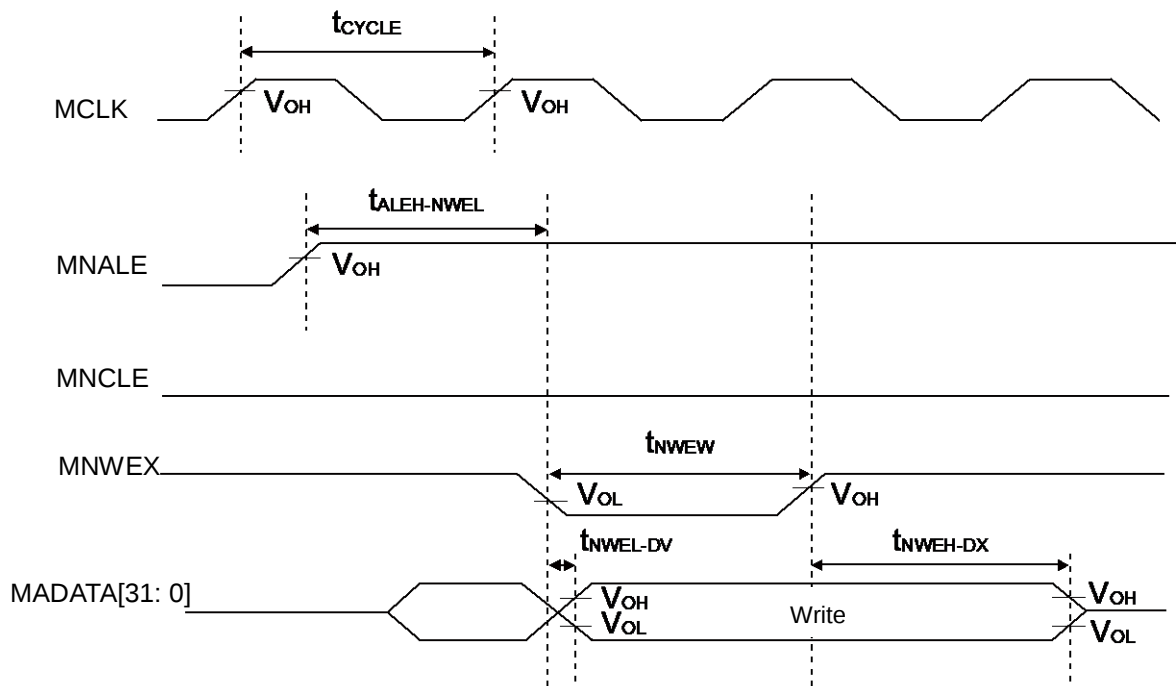
- 2. Protection of Output Pins**

Shorting of output pins to supply pins or other output pins, or connection to large capacitance can cause large current flows. Such conditions, if present for extended periods of time, can damage the device; therefore, avoid this type of connection.

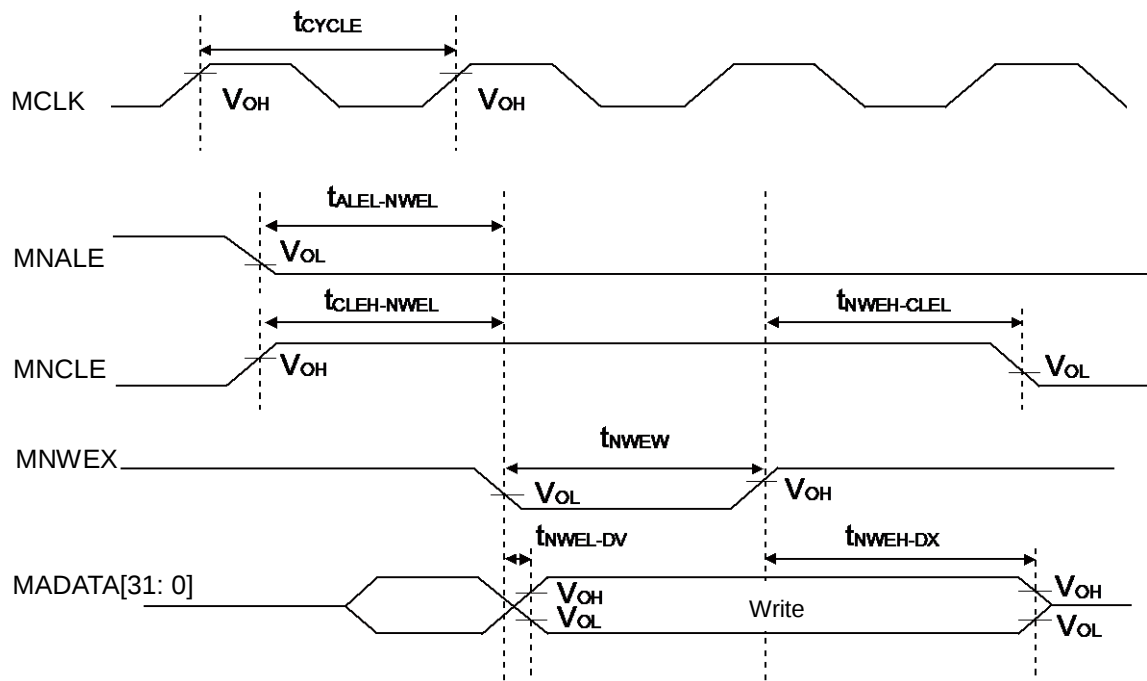
- 3. Handling of Unused Input Pins**

Unconnected input pins with very high impedance levels can adversely affect stability of operation. Such pins should be connected through an appropriate resistance to a power-supply pin or ground pin.

NAND Flash Address Write



NAND Flash Command Write



When Using Synchronous Serial Chip Select (SCINV = 0, CSLVL = 1)

(V_{CC} = 2.7V to 5.5V, V_{SS} = 0V)

Parameter	Symbol	Conditions	V _{CC} < 4.5 V		V _{CC} ≥ 4.5 V		Unit
			Min	Max	Min	Max	
SCS↓→SCK↓ setup time	t _{CSSI}	Internal shift clock operation	(*1)-50	(*1)+0	(*1)-50	(*1)+0	ns
SCK↑→SCS↑ hold time	t _{CSHI}		(*2)+0	(*2)+50	(*2)+0	(*2)+50	ns
SCS deselect time	t _{CSDI}		(*3)-50 +5t _{CYCP}	(*3)+50 +5t _{CYCP}	(*3)-50 +5t _{CYCP}	(*3)+50 +5t _{CYCP}	ns
SCS↓→SCK↓ setup time	t _{CSSE}	External shift clock operation	3t _{CYCP} +30	-	3t _{CYCP} +30	-	ns
SCK↑→SCS↑ hold time	t _{CSHE}		0	-	0	-	ns
SCS deselect time	t _{CSDE}		3t _{CYCP} +30	-	3t _{CYCP} +30	-	ns
SCS ↓ →SOT delay time	t _{DSE}		-	40	-	40	ns
SCS ↑ →SOT delay time	t _{DSE}		0	-	0	-	ns

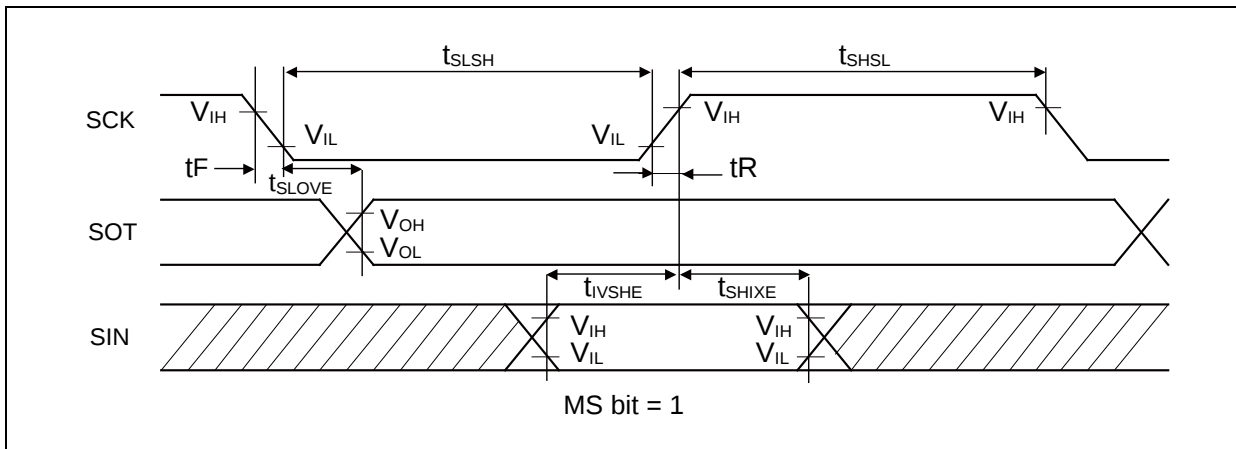
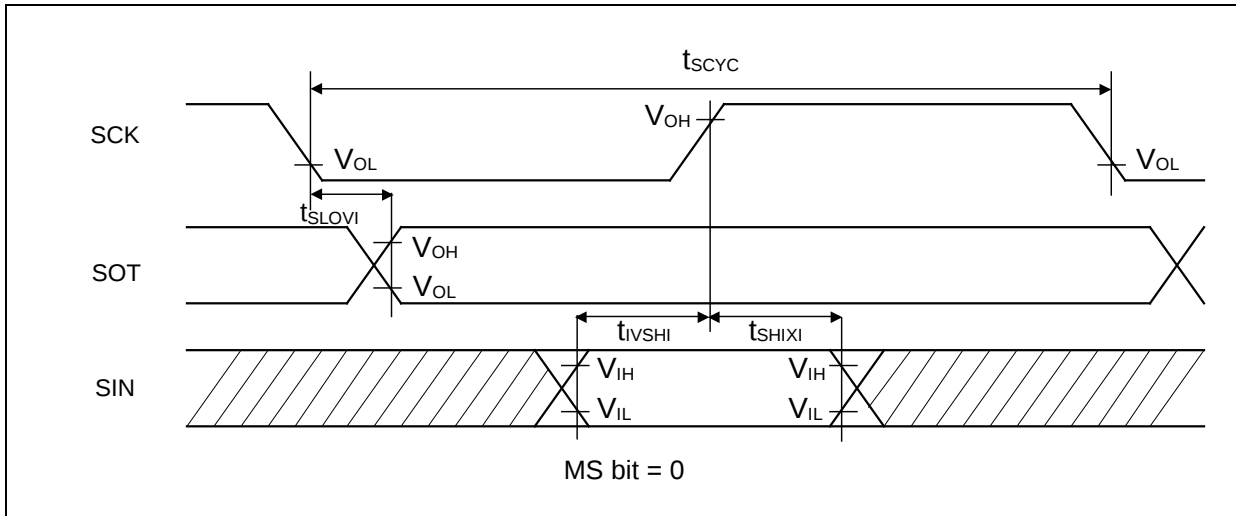
(*1): CSSU bit value×serial chip select timing operating clock cycle [ns]

(*2): CSHD bit value×serial chip select timing operating clock cycle [ns]

(*3): CSDS bit value×serial chip select timing operating clock cycle [ns]

Notes:

- t_{CYCP} indicates the APB bus clock cycle time. For more information about the APB bus number to which the multi-function serial is connected, see 8. Block Diagram in this data sheet.
- For more information about CSSU, CSHD, CSDS, and the serial chip select timing operating clock, see FM4 Family Peripheral Manual Main Part (002-04856).
- When the external load capacitance C_L = 30 pF.



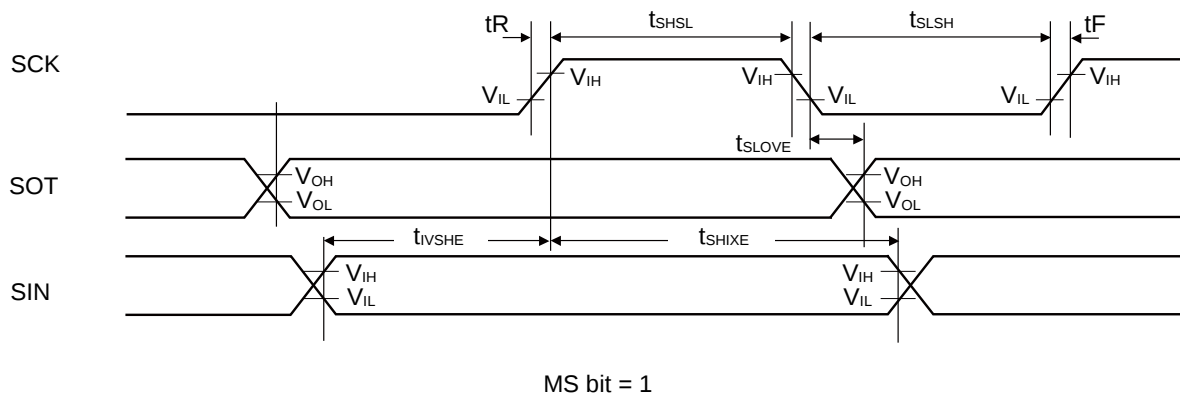
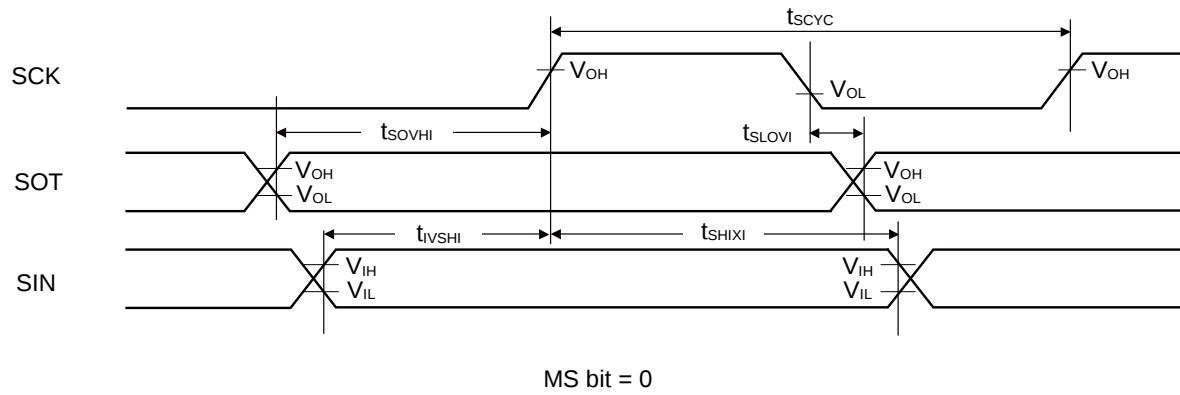
High-Speed Synchronous Serial (SPI = 0, SCINV = 1)

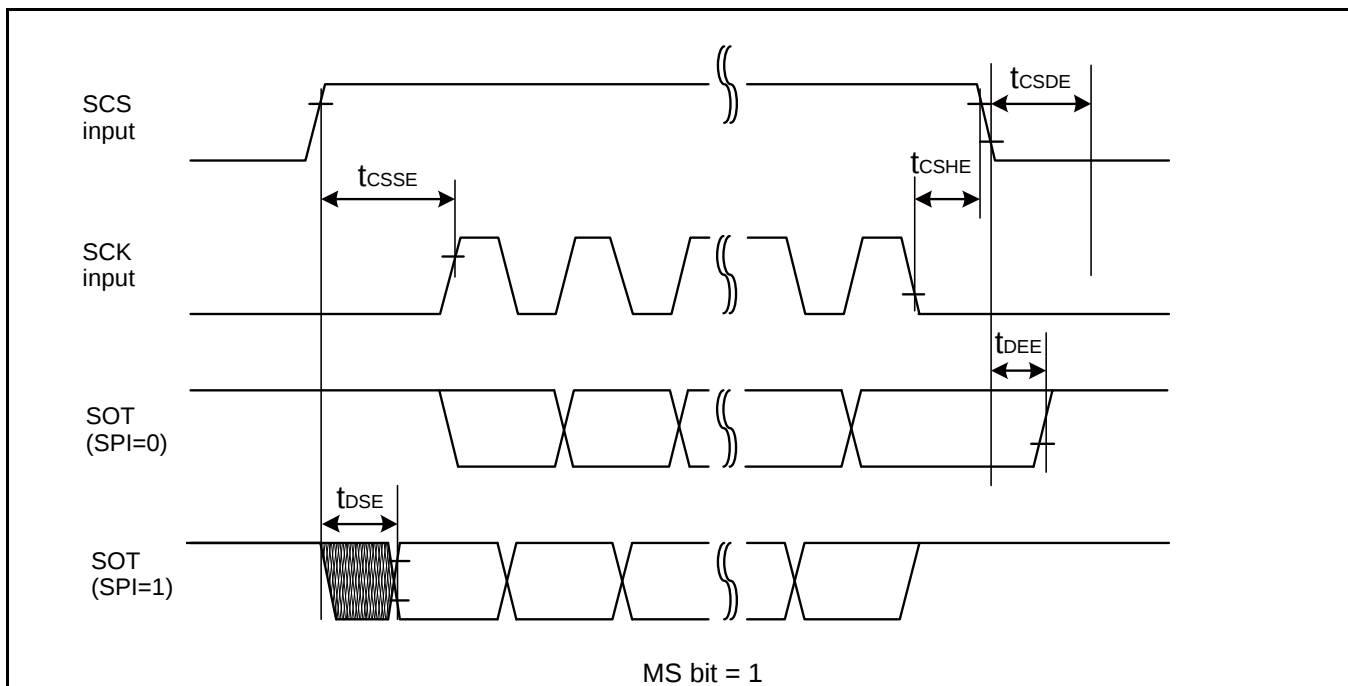
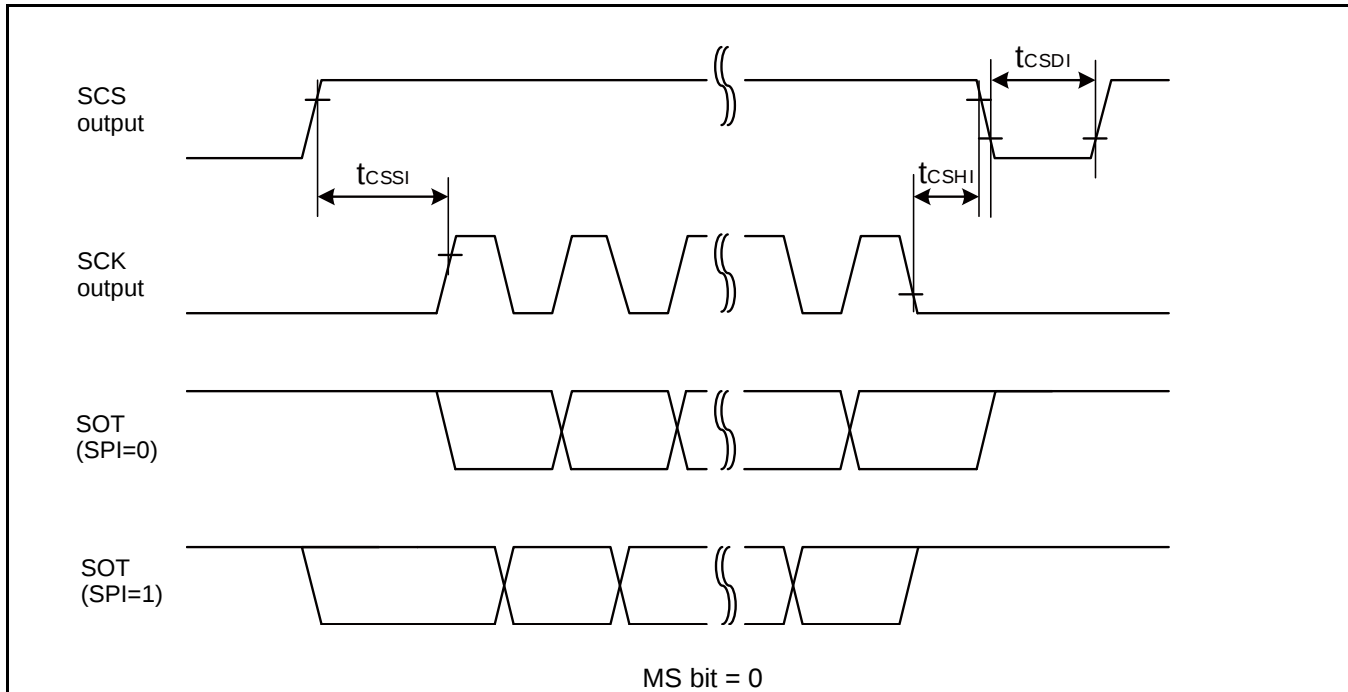
(V_{CC} = 2.7V to 5.5V, V_{SS} = 0V)

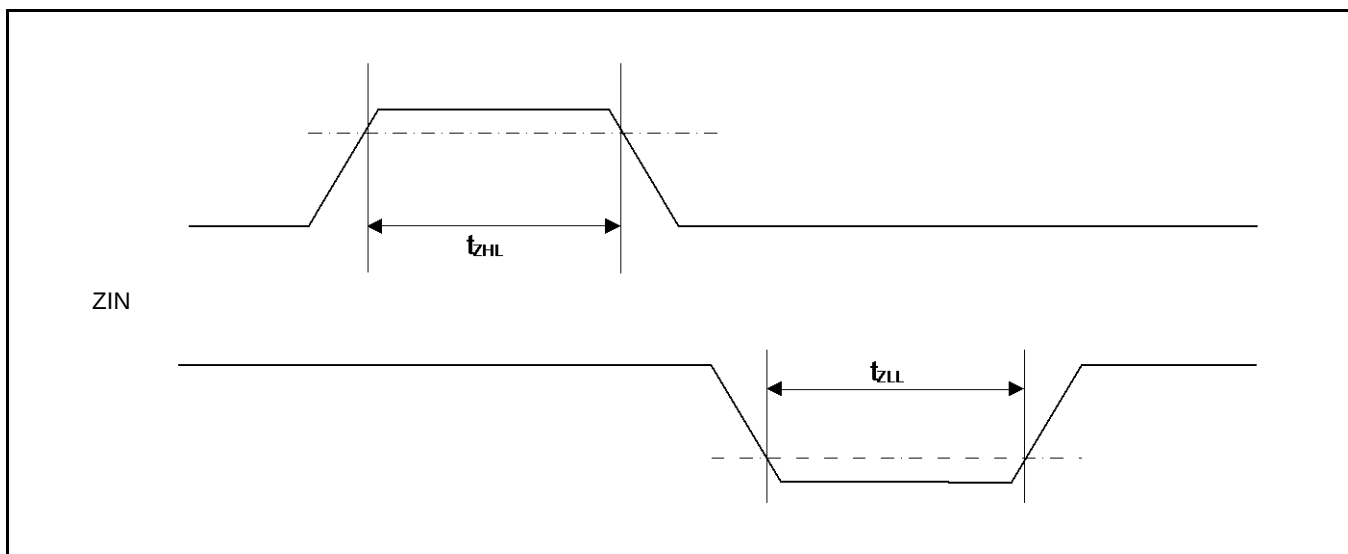
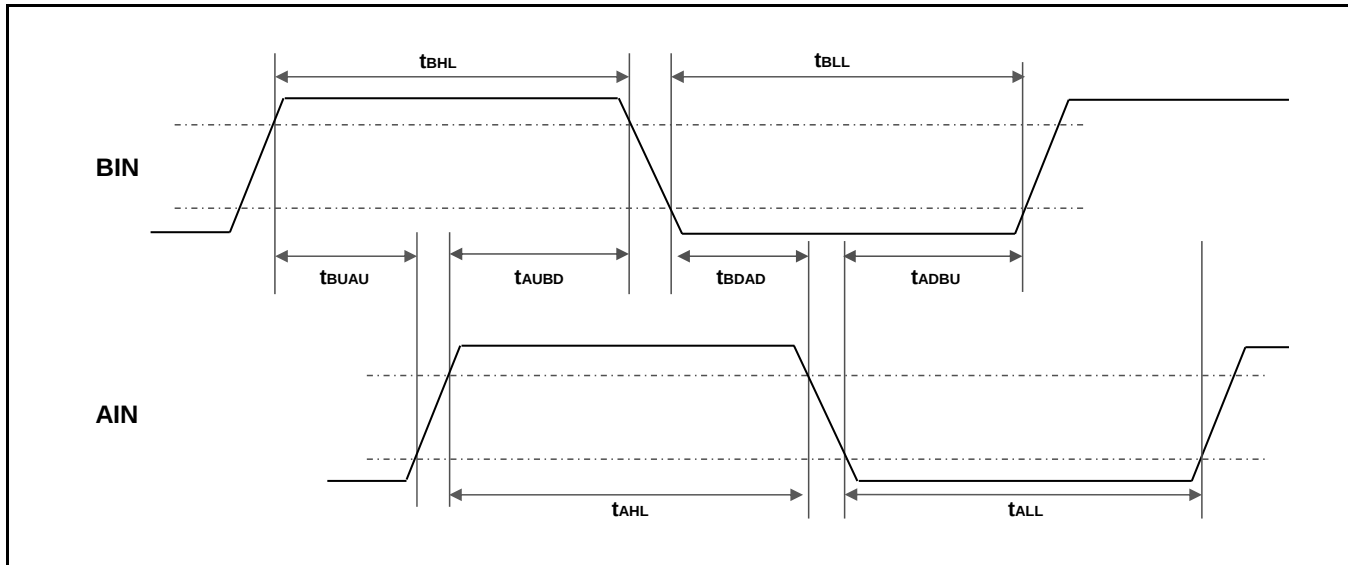
Parameter	Symbol	Pin Name	Conditions	V _{CC} < 4.5 V		V _{CC} ≥ 4.5 V		Unit
				Min	Max	Min	Max	
Serial clock cycle time	t _{SCYC}	SCKx	Internal shift clock operation	4t _{CYCP}	-	4t _{CYCP}	-	ns
SCK↑→SOT delay time	t _{SHOVI}	SCKx, SOTx		- 10	+ 10	- 10	+ 10	ns
SIN→SCK↓ setup time	t _{IVSLI}	SCKx, SINx		14	-	12.5	-	ns
				12.5*				
SCK↓→SIN hold time	t _{SLIXI}	SCKx, SINx		5	-	5	-	ns
Serial clock L pulse width	t _{SLSH}	SCKx	External shift clock operation	2t _{CYCP} - 5	-	2t _{CYCP} - 5	-	ns
Serial clock H pulse width	t _{SHSL}	SCKx		t _{CYCP} + 10	-	t _{CYCP} + 10	-	ns
SCK↑→SOT delay time	t _{SHOVE}	SCKx, SOTx		-	15	-	15	ns
SIN→SCK↓ setup time	t _{IVSLE}	SCKx, SINx		5	-	5	-	ns
SCK↓→SIN hold time	t _{SLIXE}	SCKx, SINx		5	-	5	-	ns
SCK fall time	t _F	SCKx		-	5	-	5	ns
SCK rise time	t _R	SCKx		-	5	-	5	ns

Notes:

- The above characteristics apply to CLK synchronous mode.
- t_{CYCP} indicates the APB bus clock cycle time. For more information about the APB bus number to which the multi-function serial is connected, see 8. Block Diagram in this data sheet.
- These characteristics only guarantee the following pins:
 No chip select: SIN4_0, SOT4_0, SCK4_0
 Chip select: SIN6_0, SOT6_0, SCK6_0, SCS60_0, SCS61_0, SCS62_0, SCS63_0
- When the external load capacitance C_L = 30 pF. (For *, when C_L = 10 pF)







High-Speed Mode

■ Clock CLK (All values are referred to V_{IH} and V_{IL})

($V_{CC} = 2.7V$ to $3.6V$, $V_{SS} = 0V$)

Parameter	Symbol	Pin Name	Conditions	Value		Remarks
				Min	Max	
Clock frequency Data Transfer Mode	f_{PP}	S_CLK	$C_{CARD} \leq 10$ pF (1 card)	0	50	MHz
Clock low time	t_{WL}	S_CLK		7	-	ns
Clock high time	t_{WH}	S_CLK		7	-	ns
Clock rise time	t_{TLH}	S_CLK		-	3	ns
Clock fall time	t_{THL}	S_CLK		-	3	ns

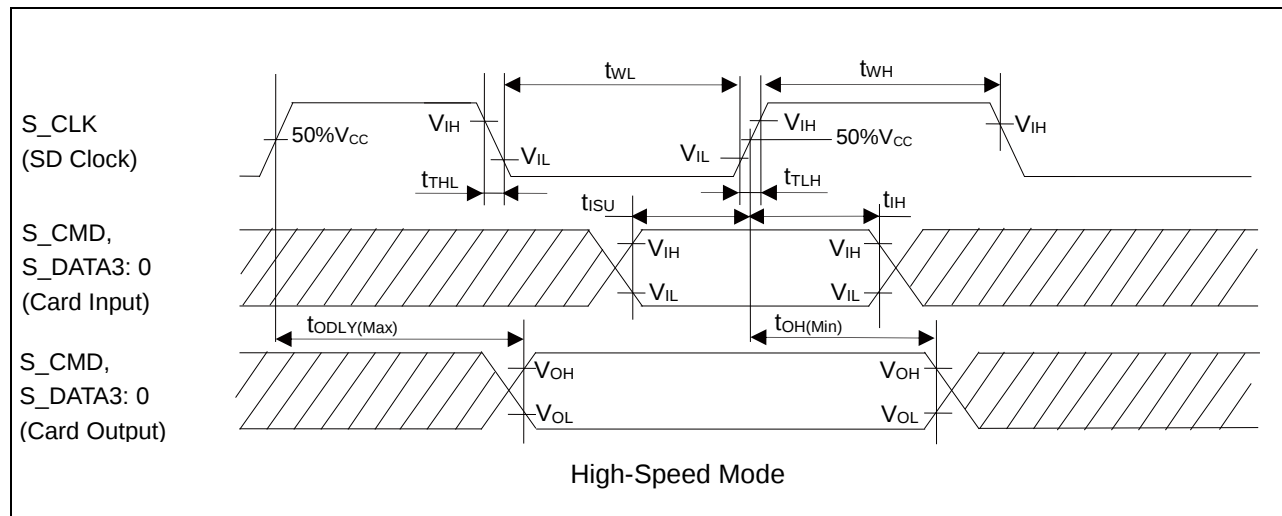
■ Card Inputs CMD, DAT (referenced to Clock CLK)

Parameter	Symbol	Pin Name	Conditions	Value		Remarks
				Min	Max	
Input set-up time	t_{ISU}	S_CMD, S_DATA3: 0	$C_{CARD} \leq 10$ pF (1 card)	6	-	ns
Input hold time	t_{IH}	S_CMD, S_DATA3: 0		2	-	ns

■ Card Outputs CMD, DAT (referenced to Clock CLK)

Parameter	Symbol	Pin Name	Conditions	Value		Remarks
				Min	Max	
Output delay time during data transfer mode	t_{ODLY}	S_CMD, S_DATA3: 0	$C_L \leq 40$ pF (1 card)	0	14	ns
Output hold time	t_{OH}	S_CMD, S_DATA3: 0	$C_L \geq 15$ pF (1 card)	2.5	-	ns
Total system capacitance for each line*	C_L	-	1 card	-	40	pF

*: In order to satisfy severe timing, host shall drive only one card.

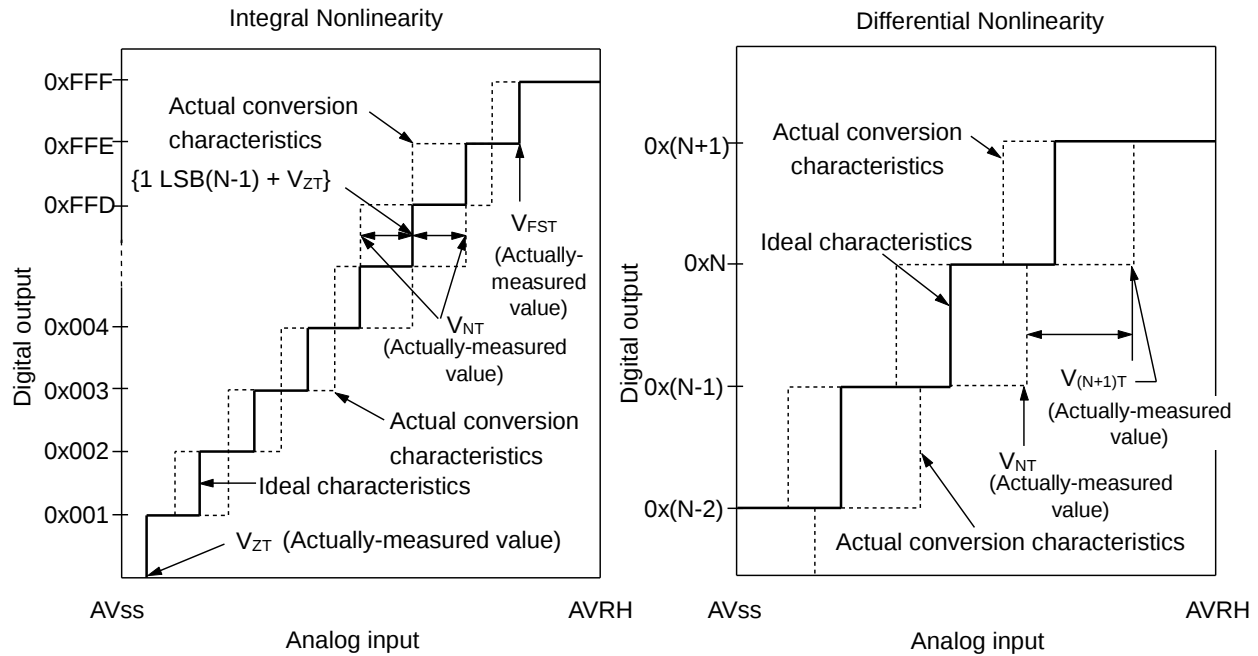


Notes:

- The Card Input corresponds to the Host Output and the Card Output corresponds to the Host Input because this model is the Host.
- For more information about clock frequency (f_{PP}), see Chapter 15: SD card Interface in FM4 Family Peripheral Manual Main Part (002-04856).

Definition of 12-bit A/D Converter Terms

- **Resolution:** Analog variation that is recognized by an A/D converter.
- **Integral Nonlinearity:** Deviation of the line between the zero-transition point (0b000000000000 ↔ 0b000000000001) and the full-scale transition point (0b111111111110 ↔ 0b111111111111) from the actual conversion characteristics.
- **Differential Nonlinearity:** Deviation from the ideal value of the input voltage that is required to change the output code by 1 LSB.



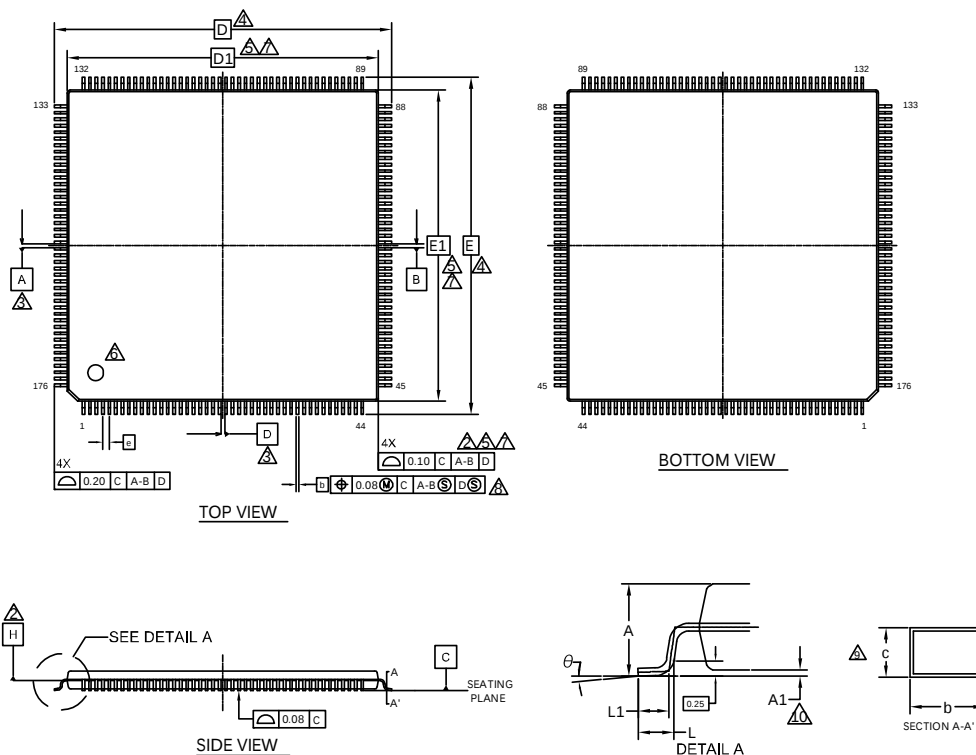
$$\text{Integral Nonlinearity of digital output } N = \frac{V_{NT} - \{1\text{LSB} \times (N - 1) + V_{ZT}\}}{1\text{LSB}} \quad [\text{LSB}]$$

$$\text{Differential Nonlinearity of digital output } N = \frac{V_{(N+1)T} - V_{NT}}{1\text{LSB}} - 1 \quad [\text{LSB}]$$

$$1\text{LSB} = \frac{V_{FST} - V_{ZT}}{4094}$$

- N: A/D converter digital output value.
- V_{ZT} : Voltage at which the digital output changes from 0x000 to 0x001.
- V_{FST} : Voltage at which the digital output changes from 0xFFE to 0xFFF.
- V_{NT} : Voltage at which the digital output changes from 0x(N - 1) to 0xN.

Package Type	Package Code
LQFP 176	LQP 176



SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.
A	—	—	1.70
A1	0.05	—	0.15
b	0.17	0.22	0.27
c	0.09	—	0.20
D	26.00 BSC		
D1	24.00 BSC		
e	0.50 BSC		
E	26.00 BSC		
E1	24.00 BSC		
L	0.45	0.60	0.75
L1	0.30	0.50	0.70
θ	0°	—	8°

NOTES

- ALL DIMENSIONS ARE IN MILLIMETERS.
- DATUM PLANE H IS LOCATED AT THE BOTTOM OF THE MOLD PARTING LINE COINCIDENT WITH WHERE THE LEAD EXITS THE BODY.
- DATUMS A-B AND D TO BE DETERMINED AT DATUM PLANE H.
- TO BE DETERMINED AT SEATING PLANE C.
- DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.25mm PRE SIDE. DIMENSIONS D1 AND E1 INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE H.
- DETAILS OF PIN 1 IDENTIFIER ARE OPTIONAL BUT MUST BE LOCATED WITHIN THE ZONE INDICATED.
- REGARDLESS OF THE RELATIVE SIZE OF THE UPPER AND LOWER BODY SECTIONS, DIMENSIONS D1 AND E1 ARE DETERMINED AT THE LARGEST FEATURE OF THE BODY EXCLUSIVE OF MOLD FLASH AND GATE BURRS. BUT INCLUDING ANY MISMATCH BETWEEN THE UPPER AND LOWER SECTIONS OF THE MOLDER BODY.
- DIMENSION b DOES NOT INCLUDE DAMBER PROTRUSION. THE DAMBER PROTRUSION (S) SHALL NOT CAUSE THE LEAD WIDTH TO EXCEED b MAXIMUM BY MORE THAN 0.08mm. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE LEAD FOOT.
- THESE DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN 0.10mm AND 0.25mm FROM THE LEAD TIP.
- A1 IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT OF THE PACKAGE BODY.

002-15150 **

PACKAGE OUTLINE, 176 LEAD LQFP
24.0X24.0X1.7 MM LQP176 REV**

15. Major Changes

Spancion Publication Number: DS709-00010

Page	Section	Change Results
Revision 0.1		
-	-	Initial release
Revision 1.0		
7 15	2. Features 3. Product Lineup	Added that CAN-FD Interface supported non-CAN FD.
12 15 90 91	2. Features 3. Product Lineup 10. Block Diagram 12. Memory Map	Deleted HDM-CEC/Remote Control Receiver.
18-20	5. Pin Assignments	Deleted the pins of HDM-CEC/Remote Control Receiver.(CEC0,CEC1) Revised the pin name of I2S. (MI2S*_0→MI2S*0_0) Deleted the pin of IGTRG0_0.
22-74	6. Pin Descriptions	Deleted the pins of HDM-CEC/Remote Control Receiver.(CEC0,CEC1) Revised the pin name of I2S. (MI2S*_0→MI2S*0_0) Revised the pin number of PF7 in LQFP216.(91→90) Revised the pin number of X1. (73, 58, 50, P5→107, 87, 71, P13) Revised the pin number of X0A. (107, 87, 71, P13→73, 58, 50, P5)
75-82	7. I/O Circuit Type	Revised IOH/IOL of Type S.(IOH=-12mA→-10mA, IOL=12mA→10mA) Added the case of using I2C in Type E, F, G, L, N, S.
97-105	13. Pin Status In Each CPU State	Deleted X and Y in Pin Status Type.
106-107	14.1. Absolute Maximum Ratings	Added 10 mA type.
108-111	14.2. Recommended Operating Conditions	Added AVRL in Analog reference voltage. Revised the leakage current in Maximum leakage current at operating
112-121	14.3.1. Current Rating	Revised the maximum current of each category.
122-123	14.3.2. Pin Characteristics	Added the characteristic of external bus in H level input voltage (hysteresis input). Added the characteristic of 10 mA type.
126	14.4.5. Operating Conditions of USB PLL · I2S PLL (in the case of using main clock for input clock of PLL)	Revised the maximum of I2S PLL macro oscillation clock frequency. (307.2 MHz→384 MHz)
190	14.5.12-bit A/D Converter	Revised the minimum of Sampling time. Revised the characteristic of State transition time to operation permission Added AVRL in Analog reference voltage.
198	14.8.2. Interrupt of Low-Voltage Detection	Revised the SVHI values in Conditions

NOTE: Please see “Document History” about later revised information.